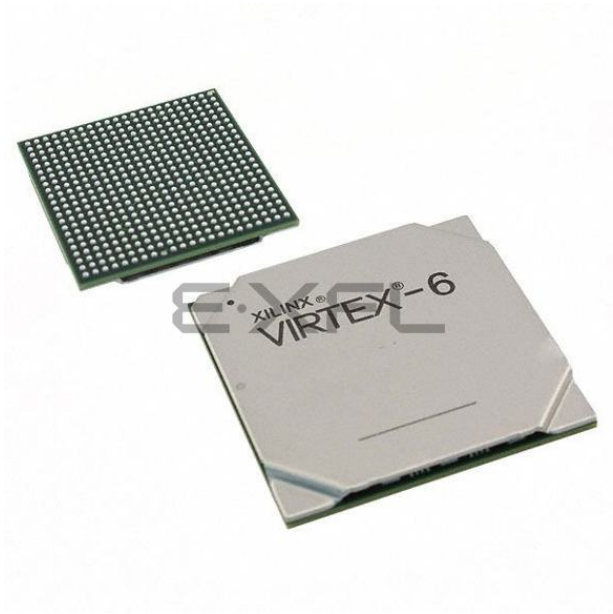
AMD Xilinx - XC6VSX315T-1FF1759I Datasheet



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Details	
Product Status	Active
Number of LABs/CLBs	24600
Number of Logic Elements/Cells	314880
Total RAM Bits	25952256
Number of I/O	720
Number of Gates	-
Voltage - Supply	0.95V ~ 1.05V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	1759-BBGA, FCBGA
Supplier Device Package	1759-FCBGA (42.5x42.5)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc6vsx315t-1ff1759i

Table 2: **Recommended Operating Conditions**

Symbol	Description	Min	Max	Units
V_{CCINT}	Internal supply voltage relative to GND for all devices except -1L devices.	0.95	1.05	V
	For -1L commercial temperature range devices: internal supply voltage relative to GND, T_j = 0°C to +85°C	0.87	0.93	V
	For -1L industrial temperature range devices: internal supply voltage relative to GND, T_j = –40°C to +100°C	0.91	0.97	V
V_{CCAUX}	Auxiliary supply voltage relative to GND	2.375	2.625	V
V_{CCO}(1)(2)(3)	Supply voltage relative to GND	1.14	2.625	V
V_{IN}	2.5V supply voltage relative to GND	GND – 0.20	2.625	V
	2.5V and below supply voltage relative to GND	GND – 0.20	V_{CCO} + 0.2	V
I_{IN}(5)	Maximum current through any pin in a powered or unpowered bank when forward biasing the clamp diode.	–	10	mA
V_{BATT}(6)	Battery voltage relative to GND	1.0	2.5	V
V_{FS}(7)	External voltage supply for eFUSE programming	2.375	2.625	V
T_j	Junction temperature operating range for commercial (C) temperature devices	0	85	°C
	Junction temperature operating range for extended (E) temperature devices	0	100	°C
	Junction temperature operating range for industrial (I) temperature devices	–40	100	°C
	Junction temperature operating range for military (M) temperature devices	–55	125	°C

Notes:

1. Configuration data is retained even if V_{CCO} drops to 0V.
2. Includes V_{CCO} of 1.2V, 1.5V, 1.8V, and 2.5V.
3. The configuration supply voltage V_{CC_CONFIG} is also known as V_{CCO_0}.
4. All voltages are relative to ground.
5. A total of 100 mA per bank should not be exceeded.
6. V_{BATT} is required only when using bitstream encryption. If battery is not used, connect V_{BATT} to either ground or V_{CCAUX}.
7. During eFUSE programming, V_{FS} must be within the recommended operating range and T_j = +15°C to +85°C. Otherwise, V_{FS} can be connected to GND.

Table 4: **Typical Quiescent Supply Current *(Cont'd)***

Symbol	Description	Device	Speed and Temperature Grade						Units
			-3 (C)	-2 (C, E, & I)	-1 (C & I)	-1 (I & M)(2)	-1L (C)	-1L (I)(1)	
I_{CCOQ}	Quiescent V_{CCO} supply current	XC6VLX75T	1	1	1	N/A	1	1	mA
		XC6VLX130T	1	1	1	N/A	1	1	mA
		XC6VLX195T	1	1	1	N/A	1	1	mA
		XC6VLX240T	2	2	2	N/A	2	2	mA
		XC6VLX365T	2	2	2	N/A	2	2	mA
		XC6VLX550T(3)	N/A	3	3	N/A	3	3	mA
		XC6VLX760(3)	N/A	3	3	N/A	3	3	mA
		XC6VSX315T	2	2	2	N/A	2	2	mA
		XC6VSX475T(3)	N/A	2	2	N/A	2	2	mA
		XC6VHX250T	1	1	1	N/A	N/A	N/A	mA
		XC6VHX255T	1	1	1	N/A	N/A	N/A	mA
		XC6VHX380T(4)	2	2	2	N/A	N/A	N/A	mA
		XC6VHX565T(5)	N/A	2	2	N/A	N/A	N/A	mA
		XQ6VLX130T	N/A	1	N/A	1	N/A	1	mA
		XQ6VLX240T	N/A	2	N/A	2	N/A	2	mA
		XQ6VLX550T(7)	N/A	N/A	N/A	3	N/A	3	mA
		XQ6VSX315T	N/A	2	N/A	2	N/A	2	mA
		XQ6VSX475T(7)	N/A	N/A	N/A	2	N/A	2	mA

Table 4: **Typical Quiescent Supply Current *(Cont'd)***

Symbol	Description	Device	Speed and Temperature Grade						Units
			-3 (C)	-2 (C, E, & I)	-1 (C & I)	-1 (I & M)(2)	-1L (C)	-1L (I)(1)	
I_{CCAUXQ}	Quiescent V_{CCAUX} supply current	XC6VLX75T	45	45	45	N/A	45	45	mA
		XC6VLX130T	75	75	75	N/A	75	75	mA
		XC6VLX195T	113	113	113	N/A	113	113	mA
		XC6VLX240T	135	135	135	N/A	135	135	mA
		XC6VLX365T	191	191	191	N/A	191	191	mA
		XC6VLX550T(3)	N/A	286	286	N/A	286	286	mA
		XC6VLX760(3)	N/A	387	387	N/A	387	387	mA
		XC6VSX315T	186	186	186	N/A	186	186	mA
		XC6VSX475T(3)	N/A	279	279	N/A	279	279	mA
		XC6VHX250T	152	152	152	N/A	N/A	N/A	mA
		XC6VHX255T	152	152	152	N/A	N/A	N/A	mA
		XC6VHX380T(4)	227	227	227	N/A	N/A	N/A	mA
		XC6VHX565T(5)	N/A	315	315	N/A	N/A	N/A	mA
		XQ6VLX130T(6)	N/A	75	N/A	75	N/A	75	mA
		XQ6VLX240T(6)	N/A	135	N/A	135	N/A	135	mA
		XQ6VLX550T(7)	N/A	N/A	N/A	286	N/A	286	mA
		XQ6VSX315T(6)	N/A	186	N/A	186	N/A	186	mA
		XQ6VSX475T(7)	N/A	N/A	N/A	279	N/A	279	mA

Notes:

1. Typical values are specified at nominal voltage, 85°C junction temperatures (T_j). -1 and -2 industrial (I) grade devices have the same typical values as commercial (C) grade devices at 85°C, but higher values at 100°C. Use the XPE tool to calculate 100°C values. -1L industrial temperature range devices have the values specified in this column.
2. Use the XPE tool to calculate 125°C values for -1M temperature range devices.
3. The -2E extended temperature range (T_j = 0°C to +100°C) is only available in these devices. The -2I temperature range (T_j = –40°C to +100°C) is available for all other devices except the XC6VHX565T.
4. The XC6VHX380T is available with both -2E and -2I temperature ranges.
5. The XC6VHX565T is only available in the following temperature ranges: -1C, -1I, -2C, and -2E.
6. The XQ6VLX130T, XQ6VLX240T, and XQ6VSX315T are available in -2I, -1I, -1M, and -1LI temperature ranges.
7. The XQ6VLX550T and the XQ6VSX475T are only available in -1I and -1LI temperature ranges.
8. Typical values are for blank configured devices with no output current loads, no active input pull-up resistors, all I/O pins are 3-state and floating.
9. If DCI or differential signaling is used, more accurate quiescent current estimates can be obtained by using the XPE or XPower Analyzer (XPA) tools.

HT DC Specifications (HT_25)

Table 8: **HT DC Specifications**

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
V_{CCO}	Supply Voltage		2.38	2.5	2.63	V
V_{OD}	Differential Output Voltage for XC devices	R_T = 100 Ω across Q and $\overline{Q}$ signals	480	600	885	mV
	Differential Output Voltage for XQ devices		480	600	930	mV
ΔV_{OD}	Change in V_{OD} Magnitude		–15	–	15	mV
V_{OCM}	Output Common Mode Voltage	R_T = 100 Ω across Q and $\overline{Q}$ signals	440	600	760	mV
ΔV_{OCM}	Change in V_{OCM} Magnitude		–15	–	15	mV
V_{ID}	Input Differential Voltage		200	600	1000	mV
ΔV_{ID}	Change in V_{ID} Magnitude		–15	–	15	mV
V_{ICM}	Input Common Mode Voltage		440	600	780	mV
ΔV_{ICM}	Change in V_{ICM} Magnitude		–15	–	15	mV

LVDS DC Specifications (LVDS_25)

Table 9: **LVDS DC Specifications**

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
V_{CCO}	Supply Voltage		2.38	2.5	2.63	V
V_{OH}	Output High Voltage for Q and $\overline{Q}$	R_T = 100 Ω across Q and $\overline{Q}$ signals	–	–	1.675	V
V_{OL}	Output Low Voltage for Q and $\overline{Q}$	R_T = 100 Ω across Q and $\overline{Q}$ signals	0.825	–	–	V
V_{ODIFF}	Differential Output Voltage (Q – $\overline{Q}$), Q = High (Q – $\overline{Q}$), $\overline{Q}$ = High	R_T = 100 Ω across Q and $\overline{Q}$ signals	247	350	600	mV
V_{OCM}	Output Common-Mode Voltage for XC devices	R_T = 100 Ω across Q and $\overline{Q}$ signals	1.075	1.250	1.425	V
	Output Common-Mode Voltage for XQ devices		1.000	1.250	1.425	V
V_{IDIFF}	Differential Input Voltage (Q – $\overline{Q}$), Q = High (Q – $\overline{Q}$), $\overline{Q}$ = High		100	350	600	mV
V_{ICM}	Input Common-Mode Voltage		0.3	1.2	2.2	V

Extended LVDS DC Specifications (LVDSEXT_25)

Table 10: **Extended LVDS DC Specifications**

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
V_{CCO}	Supply Voltage		2.38	2.5	2.63	V
V_{OH}	Output High Voltage for Q and $\overline{Q}$	R_T = 100 Ω across Q and $\overline{Q}$ signals	–	–	1.785	V
V_{OL}	Output Low Voltage for Q and $\overline{Q}$	R_T = 100 Ω across Q and $\overline{Q}$ signals	0.715	–	–	V
V_{ODIFF}	Differential Output Voltage (Q – $\overline{Q}$), Q = High (Q – $\overline{Q}$), $\overline{Q}$ = High for XC devices	R_T = 100 Ω across Q and $\overline{Q}$ signals	350	–	840	mV
	Differential Output Voltage (Q – $\overline{Q}$), Q = High (Q – $\overline{Q}$), $\overline{Q}$ = High for XQ devices		350	–	850	mV
V_{OCM}	Output Common-Mode Voltage for XC devices	R_T = 100 Ω across Q and $\overline{Q}$ signals	1.075	1.250	1.425	V
	Output Common-Mode Voltage for XQ devices		1.000	1.250	1.425	V
V_{IDIFF}	Differential Input Voltage (Q – $\overline{Q}$), Q = High (Q – $\overline{Q}$), $\overline{Q}$ = High	Common-mode input voltage = 1.25V	100	–	1000	mV
V_{ICM}	Input Common-Mode Voltage	Differential input voltage = ±350 mV	0.3	1.2	2.2	V

GTX Transceiver Specifications

GTX Transceiver DC Characteristics

Table 13: **Absolute Maximum Ratings for GTX Transceivers(1)**

Symbol	Description	Min	Max	Units
MGTAVCC	Analog supply voltage for the GTX transmitter and receiver circuits relative to GND	–0.5	1.1	V
MGTAVTT	Analog supply voltage for the GTX transmitter and receiver termination circuits relative to GND	–0.5	1.32	V
MGTAVTTRCAL	Analog supply voltage for the resistor calibration circuit of the GTX transceiver column	–0.5	1.32	V
V_{IN}	Receiver (RXP/RXN) and Transmitter (TXP/TXN) absolute input voltage	–0.5	1.32	V
$V_{MGTREFCLK}$	Reference clock absolute input voltage	–0.5	1.32	V

Notes:

1. Stresses beyond those listed under Absolute Maximum Ratings might cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those listed under Operating Conditions is not implied. Exposure to Absolute Maximum Ratings conditions for extended periods of time might affect device reliability.

Table 14: **Recommended Operating Conditions for GTX Transceivers(1)(2)**

Symbol	Description	Speed Grade	PLL Frequency	Min	Typ	Max	Units
MGTAVCC	Analog supply voltage for the GTX transmitter and receiver circuits relative to GND	-3, -2(3)	> 2.7 GHz	1.0	1.03	1.06	V
		-3, -2(3)	≤ 2.7 GHz	0.95	1.0	1.06	V
		-1	≤ 2.7 GHz	0.95	1.0	1.06	V
		-1L	≤ 2.7 GHz	0.95	1.0	1.05	V
MGTAVTT	Analog supply voltage for the GTX transmitter and receiver termination circuits relative to GND	All	–	1.14	1.2	1.26	V
MGTAVTTRCAL	Analog supply voltage for the resistor calibration circuit of the GTX transceiver column	All	–	1.14	1.2	1.26	V

Notes:

1. Each voltage listed requires the filter circuit described in UG366: *Virtex-6 FPGA GTX Transceivers User Guide*.
2. Voltages are specified for the temperature range of T_j = –40°C to +100°C for all XC devices and T_j = –55°C to +125°C for the XQ devices
3. If a GTX Quad contains transceivers operating with a mixture of PLL frequencies above and below 2.7 GHz, the MGTAVCC voltage supply must be in the range of 1.0V to 1.06V.

Table 15: **GTX Transceiver Supply Current (per Lane) (1)(2)**

Symbol	Description	Typ	Max	Units
$I_{MGTAVTT}$	MGTAVTT supply current for one GTX transceiver	55.9	Note 2	mA
$I_{MGTAVCC}$	MGTAVCC supply current for one GTX transceiver	56.1		mA
$MGTR_{REF}$	Precision reference resistor for internal calibration termination	100.0 ± 1% tolerance		Ω

Notes:

1. Typical values are specified at nominal voltage, 25°C, with a 3.125 Gb/s line rate.
2. Values for currents of other transceiver configurations and conditions can be obtained by using the XPower Estimator (XPE) or XPower Analyzer (XPA) tools.

Table 23: **GTX Transceiver Transmitter Switching Characteristics**

Symbol	Description	Condition	Min	Typ	Max	Units
F_{GTXTX}	Serial data rate range		0.480	–	F_{GTXMAX}	Gb/s
T_{RTX}	TX Rise time	20%–80%	–	120	–	ps
T_{FTX}	TX Fall time	80%–20%	–	120	–	ps
T_{LLSKEW}	TX lane-to-lane skew(1)		–	–	350	ps
$V_{TXOOBVDPP}$	Electrical idle amplitude		–	–	15	mV
$T_{TXOOBTRANSITION}$	Electrical idle transition time		–	–	75	ns
$TJ_{6.5}$	Total Jitter(2)(3)	6.5 Gb/s	–	–	0.33	UI
$DJ_{6.5}$	Deterministic Jitter(2)(3)		–	–	0.17	UI
$TJ_{5.0}$	Total Jitter(2)(3)	5.0 Gb/s	–	–	0.33	UI
$DJ_{5.0}$	Deterministic Jitter(2)(3)		–	–	0.15	UI
$TJ_{4.25}$	Total Jitter(2)(3)	4.25 Gb/s	–	–	0.33	UI
$DJ_{4.25}$	Deterministic Jitter(2)(3)		–	–	0.14	UI
$TJ_{3.75}$	Total Jitter(2)(3)	3.75 Gb/s	–	–	0.34	UI
$DJ_{3.75}$	Deterministic Jitter(2)(3)		–	–	0.16	UI
$TJ_{3.125}$	Total Jitter(2)(3)	3.125 Gb/s	–	–	0.2	UI
$DJ_{3.125}$	Deterministic Jitter(2)(3)		–	–	0.1	UI
$TJ_{3.125L}$	Total Jitter(2)(3)	3.125 Gb/s(4)	–	–	0.35	UI
$DJ_{3.125L}$	Deterministic Jitter(2)(3)		–	–	0.16	UI
$TJ_{2.5}$	Total Jitter(2)(3)	2.5 Gb/s(5)	–	–	0.20	UI
$DJ_{2.5}$	Deterministic Jitter(2)(3)		–	–	0.08	UI
$TJ_{1.25}$	Total Jitter(2)(3)	1.25 Gb/s(6)	–	–	0.15	UI
$DJ_{1.25}$	Deterministic Jitter(2)(3)		–	–	0.06	UI
TJ_{600}	Total Jitter(2)(3)	600 Mb/s	–	–	0.1	UI
DJ_{600}	Deterministic Jitter(2)(3)		–	–	0.03	UI
TJ_{480}	Total Jitter(2)(3)	480 Mb/s	–	–	0.1	UI
DJ_{480}	Deterministic Jitter(2)(3)		–	–	0.03	UI

Notes:

1. Using same REFCLK input with TXENPMAPHASEALIGN enabled for up to 12 consecutive transmitters (three fully populated GTX Quads).
2. Using PLL_DIVSEL_FB = 2, 20-bit internal data width. These values are NOT intended for protocol specific compliance determinations.
3. All jitter values are based on a bit-error ratio of $1e^{-12}$.
4. PLL frequency at 1.5625 GHz and OUTDIV = 1.
5. PLL frequency at 2.5 GHz and OUTDIV = 2.
6. PLL frequency at 2.5 GHz and OUTDIV = 4.

Figure 4 shows the timing parameters in Table 27.

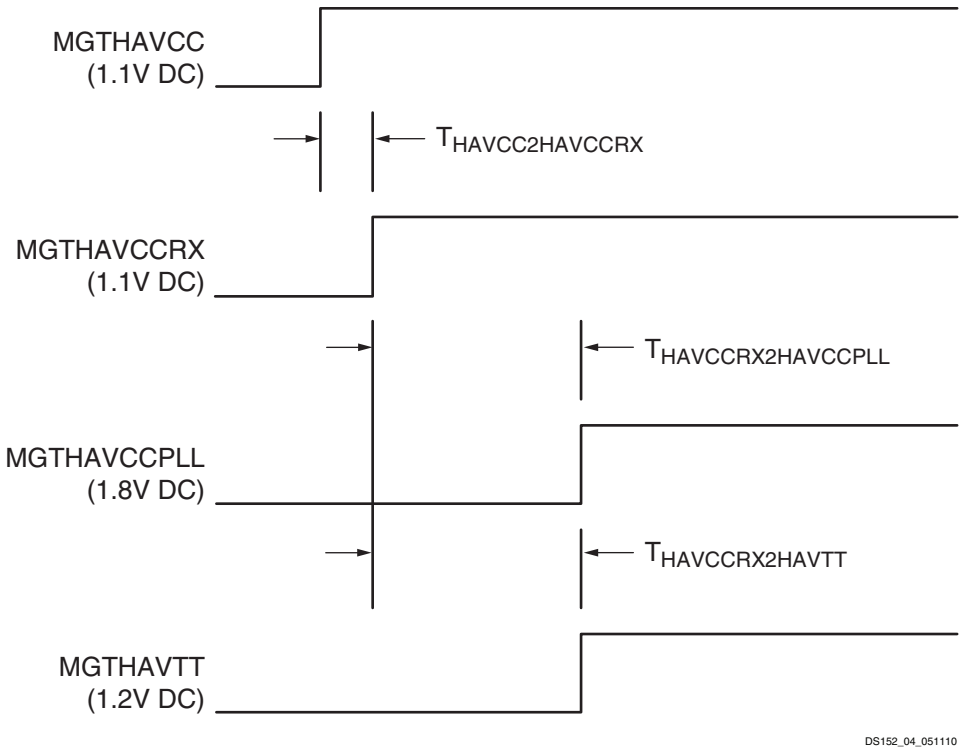

Figure 4: **GTH Transceiver Power Supply Power-On Sequencing**

Table 28: **GTH Transceiver Supply Current**

Symbol	Description	Typ(1)	Max	Units
$I_{MGTHAVCC}$	MGTHAVCC supply current for one GTH Quad (4 lanes)	571	Note 2	mA
$I_{MGTHAVCCRX}$	MGTHAVCCRX supply current for a GTH Quad (4 lanes)	254	Note 2	mA
$I_{MGTHAVTT}$	MGTHAVTT supply current for one GTH Quad (4 lanes)	93	Note 2	mA
$I_{MGTHAVCCPLL}$	MGTHAVCCPLL supply current for one GTH Quad (4 lanes)	219	Note 2	mA
$MGTR_{REF}$	Precision reference resistor for internal calibration termination	1000.0 ± 1% tolerance		Ω

Notes:

1. Typical values are specified at nominal voltage, 25°C, with a 10.3125 Gb/s line rate.
2. Values for currents other than the values specified in this table can be obtained by using the XPower Estimator (XPE) or XPower Analyzer (XPA) tools.

Table 29: **GTH Transceiver Quiescent Supply Current(1)(2)**

Symbol	Description	Typ(3)	Max	Units
$I_{MGTHAVCCQ}$	Quiescent MGTHAVCC Supply Current for one GTH Quad (4 lanes)	65	Note 4	mA
$I_{MGTHAVCCRXQ}$	Quiescent MGTHAVCCRX Supply Current for one GTH Quad (4 lanes)	17	Note 4	mA
$I_{MGTHAVTTQ}$	Quiescent MGTHAVTT Supply Current for one GTH Quad (4 lanes)	1	Note 4	mA
$I_{MGTHAVCCPLLQ}$	Quiescent MGTHAVCCPLL Supply Current for one GTH Quad (4 lanes)	1	Note 4	mA

Notes:

1. Device powered and unconfigured.
2. GTH transceiver quiescent supply current for an entire device can be calculated by multiplying the values in this table by the number of available GTH transceivers.
3. Typical values are specified at nominal voltage, 25°C.
4. Currents for conditions other than values specified in this table can be obtained by using the XPE or XPA tools.

GTH Transceiver Switching Characteristics

Consult UG371: *Virtex-6 FPGA GTH Transceivers User Guide* for further information.

Table 32: **GTH Transceiver Maximum Data Rate and PLL Frequency Range**

Symbol	Description	Conditions	Speed Grade			Units
			-3	-2	-1	
F_{GTHMAX}	Maximum GTH transceiver data rate	PLL Output Divider = 1	11.182	11.182	10.32	Gb/s
		PLL Output Divider = 4	2.795	2.795	2.58	Gb/s
F_{GTHMIN}	Minimum GTH transceiver data rate(1)	PLL Output Divider = 1	9.92	9.92	9.92	Gb/s
		PLL Output Divider = 4	2.48	2.48	2.48	Gb/s
$F_{GPLLMAX}$	Maximum GTH PLL frequency		5.591	5.591	5.16	GHz
$F_{GPLLMIN}$	Minimum GTH PLL frequency		4.96	4.96	4.96	GHz

Notes:

1. Lower data rates can be achieved using FPGA logic based oversampling designs.

Table 33: **GTH Transceiver Dynamic Reconfiguration Port (DRP) Switching Characteristics**

Symbol	Description	Speed Grade			Units
		-3	-2	-1	
$F_{GTHDRPCLK}$	GTHDRPCLK maximum frequency	70	70	60	MHz

Table 34: **GTH Transceiver Reference Clock Switching Characteristics**

Symbol	Description	Conditions	All Speed Grades			Units
			Min	Typ	Max	
F_{GCLK}	Reference clock frequency range	-1 speed grade	150	–	645	MHz
		-2 and -3 speed grades	150	–	700	MHz
T_{RCLK}	Reference clock rise time	20% – 80%	–	200	–	ps
T_{FCLK}	Reference clock fall time	80% – 20%	–	200	–	ps
T_{DCREF}	Reference clock duty cycle	CLK	45	50	55	%
T_{LOCK}	Clock recovery frequency acquisition time	Initial PLL lock	–	–	2	ms
T_{PHASE}	Clock recovery phase acquisition time	Lock to data after PLL has locked to the reference clock	–	–	20	µs

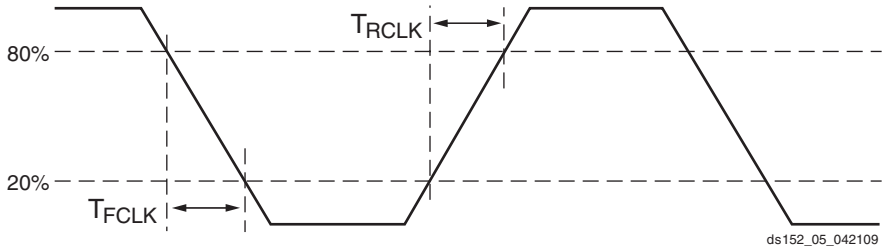

Figure 5: **Reference Clock Timing Parameters**

Table 44: **IOB Switching Characteristics for the Commercial (XC) Virtex-6 Devices *(Cont'd)***

I/O Standard	T_{IOPI}				T_{IOOP}				T_{IOTP}				Units
	Speed Grade				Speed Grade				Speed Grade				
	-3	-2	-1	-1L	-3	-2	-1	-1L	-3	-2	-1	-1L	
LVCMOS25, Fast, 24 mA	0.51	0.57	0.66	0.70	1.66	1.79	1.99	1.96	1.66	1.79	1.99	1.96	ns
LVCMOS18, Slow, 2 mA	0.55	0.61	0.71	0.73	4.21	4.47	4.87	4.30	4.21	4.47	4.87	4.30	ns
LVCMOS18, Slow, 4 mA	0.55	0.61	0.71	0.73	2.79	2.96	3.21	2.94	2.79	2.96	3.21	2.94	ns
LVCMOS18, Slow, 6 mA	0.55	0.61	0.71	0.73	2.30	2.43	2.64	2.47	2.30	2.43	2.64	2.47	ns
LVCMOS18, Slow, 8 mA	0.55	0.61	0.71	0.73	2.01	2.11	2.27	2.24	2.01	2.11	2.27	2.24	ns
LVCMOS18, Slow, 12 mA	0.55	0.61	0.71	0.73	1.88	1.99	2.15	2.10	1.88	1.99	2.15	2.10	ns
LVCMOS18, Slow, 16 mA	0.55	0.61	0.71	0.73	1.84	1.95	2.11	2.04	1.84	1.95	2.11	2.04	ns
LVCMOS18, Fast, 2 mA	0.55	0.61	0.71	0.73	4.00	4.23	4.57	4.08	4.00	4.23	4.57	4.08	ns
LVCMOS18, Fast, 4 mA	0.55	0.61	0.71	0.73	2.62	2.76	2.97	2.74	2.62	2.76	2.97	2.74	ns
LVCMOS18, Fast, 6 mA	0.55	0.61	0.71	0.73	2.15	2.28	2.46	2.32	2.15	2.28	2.46	2.32	ns
LVCMOS18, Fast, 8 mA	0.55	0.61	0.71	0.73	1.90	1.99	2.13	2.14	1.90	1.99	2.13	2.14	ns
LVCMOS18, Fast, 12 mA	0.55	0.61	0.71	0.73	1.69	1.80	1.97	1.88	1.69	1.80	1.97	1.88	ns
LVCMOS18, Fast, 16 mA	0.55	0.61	0.71	0.73	1.63	1.74	1.91	1.88	1.63	1.74	1.91	1.88	ns
LVCMOS15, Slow, 2 mA	0.64	0.73	0.85	0.85	3.43	3.77	4.29	3.91	3.43	3.77	4.29	3.91	ns
LVCMOS15, Slow, 4 mA	0.64	0.73	0.85	0.85	2.58	2.79	3.10	2.93	2.58	2.79	3.10	2.93	ns
LVCMOS15, Slow, 6 mA	0.64	0.73	0.85	0.85	2.08	2.32	2.68	2.50	2.08	2.32	2.68	2.50	ns
LVCMOS15, Slow, 8 mA	0.64	0.73	0.85	0.85	1.81	1.98	2.23	2.24	1.81	1.98	2.23	2.24	ns
LVCMOS15, Slow, 12 mA	0.64	0.73	0.85	0.85	1.76	1.91	2.13	2.07	1.76	1.91	2.13	2.07	ns
LVCMOS15, Slow, 16 mA	0.64	0.73	0.85	0.85	1.69	1.83	2.04	1.98	1.69	1.83	2.04	1.98	ns
LVCMOS15, Fast, 2 mA	0.64	0.73	0.85	0.85	3.44	3.77	4.28	3.91	3.44	3.77	4.28	3.91	ns
LVCMOS15, Fast, 4 mA	0.64	0.73	0.85	0.85	2.37	2.53	2.78	2.66	2.37	2.53	2.78	2.66	ns
LVCMOS15, Fast, 6 mA	0.64	0.73	0.85	0.85	1.80	2.05	2.42	2.16	1.80	2.05	2.42	2.16	ns
LVCMOS15, Fast, 8 mA	0.64	0.73	0.85	0.85	1.76	1.90	2.11	2.04	1.76	1.90	2.11	2.04	ns
LVCMOS15, Fast, 12 mA	0.64	0.73	0.85	0.85	1.64	1.77	1.97	1.90	1.64	1.77	1.97	1.90	ns
LVCMOS15, Fast, 16 mA	0.64	0.73	0.85	0.85	1.62	1.76	1.96	1.92	1.62	1.76	1.96	1.92	ns
LVCMOS12, Slow, 2 mA	0.72	0.81	0.93	0.95	3.14	3.39	3.75	3.54	3.14	3.39	3.75	3.54	ns
LVCMOS12, Slow, 4 mA	0.72	0.81	0.93	0.95	2.43	2.63	2.93	2.79	2.43	2.63	2.93	2.79	ns
LVCMOS12, Slow, 6 mA	0.72	0.81	0.93	0.95	1.92	2.11	2.41	2.26	1.92	2.11	2.41	2.26	ns
LVCMOS12, Slow, 8 mA	0.72	0.81	0.93	0.95	1.87	2.02	2.25	2.17	1.87	2.02	2.25	2.17	ns
LVCMOS12, Fast, 2 mA	0.72	0.81	0.93	0.95	2.71	2.98	3.39	3.11	2.71	2.98	3.39	3.11	ns
LVCMOS12, Fast, 4 mA	0.72	0.81	0.93	0.95	1.93	2.16	2.51	2.31	1.93	2.16	2.51	2.31	ns
LVCMOS12, Fast, 6 mA	0.72	0.81	0.93	0.95	1.75	1.89	2.11	2.05	1.75	1.89	2.11	2.05	ns
LVCMOS12, Fast, 8 mA	0.72	0.81	0.93	0.95	1.69	1.82	2.02	1.98	1.69	1.82	2.02	1.98	ns
LVDCI_25	0.51	0.57	0.66	0.70	2.05	2.14	2.26	2.26	2.05	2.14	2.26	2.26	ns
LVDCI_18	0.55	0.61	0.71	0.73	2.07	2.23	2.47	2.38	2.07	2.23	2.47	2.38	ns
LVDCI_15	0.64	0.73	0.85	0.85	1.85	2.01	2.24	2.18	1.85	2.01	2.24	2.18	ns

Table 48: **Output Delay Measurement Methodology *(Cont'd)***

Description	I/O Standard Attribute	R_{REF} (Ω)	C_{REF}[1] (pF)	V_{MEAS} (V)	V_{REF} (V)
HT (HyperTransport), 2.5V	LDT_25	100	0	0[2]	0.6
LVPECL (Low-Voltage Positive Emitter-Coupled Logic), 2.5V	LVPECL_25	100	0	0[2]	0
LVDCI/HSLVDCI, 2.5V	LVDCI_25, HSLVDCI_25	1M	0	1.25	0
LVDCI/HSLVDCI, 1.8V	LVDCI_18, HSLVDCI_18	1M	0	0.9	0
LVDCI/HSLVDCI, 1.5V	LVDCI_15, HSLVDCI_15	1M	0	0.75	0
HSTL (High-Speed Transceiver Logic), Class I & II, with DCI	HSTL_I_DCI, HSTL_II_DCI	50	0	V_{REF}	0.75
HSTL, Class III, with DCI	HSTL_III_DCI	50	0	0.9	1.5
HSTL, Class I & II, 1.8V, with DCI	HSTL_I_DCI_18, HSTL_II_DCI_18	50	0	V_{REF}	0.9
HSTL, Class III, 1.8V, with DCI	HSTL_III_DCI_18	50	0	1.1	1.8
SSTL (Stub Series Termi.Logic), Class I & II, 1.8V, with DCI	SSTL18_I_DCI, SSTL18_II_DCI	50	0	V_{REF}	0.9
SSTL, Class I & II, 2.5V, with DCI	SSTL2_I_DCI, SSTL2_II_DCI	50	0	V_{REF}	1.25

Notes:

1. C_{REF} is the capacitance of the probe, nominally 0 pF.
2. The value given is the differential output voltage.

Input/Output Logic Switching Characteristics

Table 49: **ILOGIC Switching Characteristics**

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
Setup/Hold						
T_{ICE1CK}/T_{ICKCE1}	CE1 pin Setup/Hold with respect to CLK	0.21/ 0.03	0.25/ 0.04	0.27/ 0.04	0.31/ 0.05	ns
T_{ISRCK}/T_{ICKSR}	SR pin Setup/Hold with respect to CLK	0.66/ –0.08	0.78/ –0.08	0.96/ –0.08	1.09/ –0.11	ns
T_{IDOCK}/T_{IOCKD}	D pin Setup/Hold with respect to CLK without Delay	0.07/ 0.41	0.08/ 0.46	0.10/ 0.54	0.11/ 0.64	ns
T_{IDOCKD}/T_{IOCKDD}	DDLY pin Setup/Hold with respect to CLK (using IODELAY)	0.10/ 0.32	0.12/ 0.36	0.14/ 0.42	0.16/ 0.50	ns
Combinatorial						
T_{IDI}	D pin to O pin propagation delay, no Delay	0.15	0.17	0.20	0.23	ns
T_{IDID}	DDLY pin to O pin propagation delay (using IODELAY)	0.19	0.22	0.25	0.28	ns
Sequential Delays						
T_{IDLO}	D pin to Q1 pin using flip-flop as a latch without Delay	0.48	0.54	0.64	0.73	ns
T_{IDLOD}	DDLY pin to Q1 pin using flip-flop as a latch (using IODELAY)	0.52	0.58	0.68	0.78	ns
T_{ICKQ}	CLK to Q outputs	0.54	0.61	0.70	0.93	ns
T_{RQ_ILOGIC}	SR pin to OQ/TQ out	0.85	0.97	1.15	1.32	ns
T_{GSRQ_ILOGIC}	Global Set/Reset to Q outputs	7.60	7.60	10.51	10.51	ns
Set/Reset						
T_{RPW_ILOGIC}	Minimum Pulse Width, SR inputs	0.78	0.95	1.20	1.30	ns, Min

Table 50: **OLOGIC Switching Characteristics**

Symbol	Description	Speed Grade					Units
		-3	-2	-1 (XC)	-1 (XQ)	-1L	
Setup/Hold							
T_{ODCK}/T_{OCKD}	D1/D2 pins Setup/Hold with respect to CLK	0.45/ –0.08	0.50/ –0.08	0.54/ –0.08	0.54/ –0.08	0.69/ –0.11	ns
T_{OOCECK}/T_{OCKOCE}	OCE pin Setup/Hold with respect to CLK	0.17/ –0.03	0.20/ –0.03	0.22/ –0.03	0.27/ –0.05	0.27/ –0.04	ns
T_{OSRCK}/T_{OCKSR}	SR pin Setup/Hold with respect to CLK	0.59/ –0.24	0.62/ –0.24	0.54/ –0.08	0.54/ –0.08	0.79/ –0.35	ns
T_{OTCK}/T_{OCKT}	T1/T2 pins Setup/Hold with respect to CLK	0.44/ –0.07	0.51/ –0.07	0.56/ –0.07	0.60/ –0.10	0.68/ –0.13	ns
T_{OTCECK}/T_{OCKTCE}	TCE pin Setup/Hold with respect to CLK	0.15/ –0.04	0.19/ –0.04	0.21/ –0.04	0.27/ –0.05	0.29/ –0.05	ns
Combinatorial							
T_{DOQ}	D1 to OQ out or T1 to TQ out	0.78	0.87	1.01	1.01	1.15	ns
Sequential Delays							
T_{OCKQ}	CLK to OQ/TQ out	0.54	0.61	0.71	0.71	0.80	ns
T_{RQ}	SR pin to OQ/TQ out	0.80	0.90	1.05	1.05	1.19	ns
T_{GSRQ}	Global Set/Reset to Q outputs	7.60	7.60	10.51	10.51	10.51	ns
Set/Reset							
T_{RPW}	Minimum Pulse Width, SR inputs	0.78	0.95	1.20	1.20	1.30	ns, Min

Input Serializer/Deserializer Switching Characteristics

Table 51: **ISERDES Switching Characteristics**

Symbol	Description	Speed Grade					Units
		-3	-2	-1 (XC)	-1 (XQ)	-1L	
Setup/Hold for Control Lines							
$T_{ISCCK\_BITSLIP}$/ $T_{ISCKC\_BITSLIP}$	BITSLIP pin Setup/Hold with respect to CLKDIV	0.07/ 0.15	0.08/ 0.16	0.09/ 0.17	0.09/ 0.17	0.14/ 0.17	ns
T_{ISCCK_CE} / T_{ISCKC_CE}(2)	CE pin Setup/Hold with respect to CLK (for CE1)	0.20/ 0.03	0.25/ 0.04	0.27/ 0.04	0.27/ 0.04	0.31/ 0.05	ns
T_{ISCCK_CE2} / T_{ISCKC_CE2}(2)	CE pin Setup/Hold with respect to CLKDIV (for CE2)	0.01/ 0.27	0.01 0.29	0.01/ 0.31	0.01/ 0.31	–0.05/ 0.35	ns
Setup/Hold for Data Lines							
T_{ISDCK_D} /T_{ISCKD_D}	D pin Setup/Hold with respect to CLK	0.07/ 0.08	0.08/ 0.09	0.09/ 0.11	0.09/ 0.11	0.11/ 0.19	ns
T_{ISDCK_DDLY} /T_{ISCKD_DDLY}	DDLY pin Setup/Hold with respect to CLK (using IODELAY)(1)	0.10/ 0.05	0.12/ 0.06	0.14/ 0.07	0.14/ 0.07	0.16/ 0.15	ns
$T_{ISDCK\_D\_DDR}$ /$T_{ISCKD\_D\_DDR}$	D pin Setup/Hold with respect to CLK at DDR mode	0.07/ 0.08	0.08/ 0.09	0.09/ 0.11	0.09/ 0.11	0.11/ 0.19	ns
$T_{ISDCK\_DDLY\_DDR}$ $T_{ISCKD\_DDLY\_DDR}$	D pin Setup/Hold with respect to CLK at DDR mode (using IODELAY)(1)	0.10/ 0.05	0.12/ 0.06	0.14/ 0.07	0.14/ 0.07	0.16/ 0.15	ns
Sequential Delays							
T_{ISCKO_Q}	CLKDIV to out at Q pin	0.57	0.66	0.75	0.80	0.88	ns
Propagation Delays							
T_{ISDO_DO}	D input to DO output pin	0.19	0.22	0.25	0.25	0.28	ns

Notes:

1. Recorded at 0 tap value.
2. T_{ISCCK_CE2} and T_{ISCKC_CE2} are reported as T_{ISCCK_CE}/T_{ISCKC_CE} in TRACE report.

Output Serializer/Deserializer Switching Characteristics

Table 52: **OSERDES Switching Characteristics**

Symbol	Description	Speed Grade					Units
		-3	-2	-1 (XC)	-1 (XQ)	-1L	
Setup/Hold							
T_{OSDCK_D}/T_{OSCKD_D}	D input Setup/Hold with respect to CLKDIV	0.23/ –0.10	0.28/ –0.10	0.31/ –0.10	0.35/ –0.10	0.36/ –0.15	ns
T_{OSDCK_T}/T_{OSCKD_T}(1)	T input Setup/Hold with respect to CLK	0.44/ –0.10	0.51/ –0.09	0.56/ –0.08	0.60/ –0.08	0.68/ –0.15	ns
$T_{OSDCK\_T2}/T_{OSCKD\_T2}$(1)	T input Setup/Hold with respect to CLKDIV	0.25/ –0.10	0.27/ –0.09	0.31/ –0.08	0.31/ –0.08	0.47/ –0.15	ns
$T_{OSCCK\_OCE}/T_{OSCKC\_OCE}$	OCE input Setup/Hold with respect to CLK	0.17/ –0.03	0.20/ –0.03	0.22/ –0.03	0.27/ –0.03	0.27/ –0.04	ns
T_{OSCCK_S}	SR (Reset) input Setup with respect to CLKDIV	0.07	0.07	0.07	0.07	0.08	ns
$T_{OSCCK\_TCE}/T_{OSCKC\_TCE}$	TCE input Setup/Hold with respect to CLK	0.15/ –0.04	0.19/ –0.04	0.21/ –0.04	0.27/ –0.04	0.29/ –0.05	ns
Sequential Delays							
T_{OSCKO_OQ}	Clock to out from CLK to OQ	0.63	0.71	0.82	0.82	0.93	ns
T_{OSCKO_TQ}	Clock to out from CLK to TQ	0.63	0.71	0.82	0.82	0.93	ns
Combinatorial							
T_{OSDO_TTQ}	T input to TQ Out	0.76	0.84	0.97	0.97	1.11	ns

Notes:

1. T_{OSDCK_T2} and T_{OSCKD_T2} are reported as T_{OSDCK_T}/T_{OSCKD_T} in TRACE report.

DSP48E1 Switching Characteristics

Table 58: **DSP48E1 Switching Characteristics**

Symbol	Description	Speed Grade					Units
		-3	-2	-1 (XC)	-1 (XQ)	-1L	
Setup and Hold Times of Data/Control Pins to the Input Register Clock							
$T_{DSPDCK\_\{A, ACIN; B, BCIN\}\_\{AREG; BREG\}}$/ $T_{DSPCKD\_\{A, ACIN; B, BCIN\}\_\{AREG; BREG\}}$	{A, ACIN, B, BCIN} input to {A, B} register CLK	0.25/ 0.27	0.29/ 0.30	0.35/ 0.34	0.36/ 0.34	0.46/ 0.39	ns
$T_{DSPDCK\_C\_CREG}$/$T_{DSPCKD\_C\_CREG}$	C input to C register CLK	0.16/ 0.20	0.19/ 0.22	0.22/ 0.24	0.25/ 0.24	0.33/ 0.30	ns
$T_{DSPDCK\_D\_DREG}$/$T_{DSPCKD\_D\_DREG}$	D input to D register CLK	0.07/ 0.31	0.10/ 0.34	0.15/ 0.39	0.16/ 0.39	0.24/ 0.45	ns
Setup and Hold Times of Data Pins to the Pipeline Register Clock							
$T_{DSPDCK\_\{A, ACIN, B, BCIN\}\_MREG\_MULT}$/ $T_{DSPCKD\_\{A, ACIN, B, BCIN\}\_MREG\_MULT}$	{A, ACIN, B, BCIN} input to M register CLK	2.36/ 0.04	2.70/ 0.04	3.21/ 0.04	3.21/ 0.04	3.66/ 0.02	ns
$T_{DSPDCK\_\{A, D\}\_ADREG}$/ $T_{DSPCKD\_\{A, D\}\_ADREG}$	{A, D} input to AD register CLK	1.24/ 0.10	1.42/ 0.12	1.69/ 0.13	1.69/ 0.13	1.91/ 0.16	ns
Setup and Hold Times of Data/Control Pins to the Output Register Clock							
$T_{DSPDCK\_\{A, ACIN, B, BCIN\}\_PREG\_MULT}$/ $T_{DSPCKD\_\{A, ACIN, B, BCIN\}\_PREG\_MULT}$	{A, ACIN, B, BCIN} input to P register CLK using multiplier	3.83/ –0.13	4.37/ –0.13	5.20/ –0.13	5.20/ –0.13	5.94/ –0.24	ns
$T_{DSPDCK\_D\_PREG\_MULT}$/ $T_{DSPCKD\_D\_PREG\_MULT}$	D input to P register CLK	3.62/ –0.47	4.13/ –0.47	4.90/ –0.47	4.90/ –0.47	5.61/ –0.77	ns
$T_{DSPDCK\_\{A, ACIN, B, BCIN\}\_PREG}$/ $T_{DSPCKD\_\{A, ACIN, B, BCIN\}\_PREG}$	{A, ACIN, B, BCIN} input to P register CLK not using multiplier	1.59/ –0.13	1.81/ –0.13	2.15/ –0.13	2.15/ –0.13	2.44/ –0.24	ns
$T_{DSPDCK\_C\_PREG}$/ $T_{DSPCKD\_C\_PREG}$	C input to P register CLK	1.42/ –0.10	1.61/ –0.10	1.91/ –0.10	1.91/ –0.10	2.16/ –0.19	ns
$T_{DSPDCK\_\{PCIN, CARRYCASCIN, MULTSIGNIN\}\_PREG}$/ $T_{DSPCKD\_\{PCIN, CARRYCASCIN, MULTSIGNIN\}\_PREG}$	{PCIN, CARRYCASCIN, MULTSIGNIN} input to P register CLK	1.23/ –0.02	1.41/ –0.02	1.67/ –0.02	1.67/ –0.02	1.91/ –0.07	ns
Setup and Hold Times of the CE Pins							
$T_{DSPDCK\_\{CEA; CEB\}\_\{AREG; BREG\}}$/ $T_{DSPCKD\_\{CEA; CEB\}\_\{AREG; BREG\}}$	{CEA; CEB} input to {A; B} register CLK	0.14/ 0.19	0.17/ 0.22	0.22/ 0.25	0.22/ 0.25	0.30/ 0.28	ns
$T_{DSPDCK\_CEC\_CREG}$/ $T_{DSPCKD\_CEC\_CREG}$	CEC input to C register CLK	0.15/ 0.18	0.18/ 0.20	0.24/ 0.23	0.24/ 0.23	0.31/ 0.26	ns
$T_{DSPDCK\_CED\_DREG}$/ $T_{DSPCKD\_CED\_DREG}$	CED input to D register CLK	0.20/ 0.12	0.24/ 0.13	0.31/ 0.14	0.31/ 0.14	0.43/ 0.16	ns
$T_{DSPDCK\_CEM\_MREG}$/ $T_{DSPCKD\_CEM\_MREG}$	CEM input to M register CLK	0.16/ 0.19	0.20/ 0.21	0.26/ 0.25	0.26/ 0.25	0.32/ 0.28	ns
$T_{DSPDCK\_CEP\_PREG}$/ $T_{DSPCKD\_CEP\_PREG}$	CEP input to P register CLK	0.32/ 0.02	0.38/ 0.02	0.46/ 0.03	0.46/ 0.03	0.54/ 0.04	ns
Setup and Hold Times of the RST Pins							
$T_{DSPDCK\_\{RSTA; RSTB\}\_\{AREG; BREG\}}$/ $T_{DSPCKD\_\{RSTA; RSTB\}\_\{AREG; BREG\}}$	{RSTA, RSTB} input to {A, B} register CLK	0.27/ 0.17	0.31/ 0.19	0.38/ 0.22	0.38/ 0.22	0.41/ 0.25	ns
$T_{DSPDCK\_RSTC\_CREG}$/ $T_{DSPCKD\_RSTC\_CREG}$	RSTC input to C register CLK	0.18/ 0.08	0.20/ 0.08	0.23/ 0.09	0.23/ 0.09	0.27/ 0.11	ns
$T_{DSPDCK\_RSTD\_DREG}$/ $T_{DSPCKD\_RSTD\_DREG}$	RSTD input to D register CLK	0.28/ 0.15	0.32/ 0.16	0.38/ 0.19	0.38/ 0.19	0.45/ 0.21	ns
$T_{DSPDCK\_RSTM\_MREG}$/ $T_{DSPCKD\_RSTM\_MREG}$	RSTM input to M register CLK	0.20/ 0.24	0.23/ 0.26	0.26/ 0.30	0.26/ 0.30	0.29/ 0.34	ns

Table 58: **DSP48E1 Switching Characteristics *(Cont'd)***

Symbol	Description	Speed Grade					Units
		-3	-2	-1 (XC)	-1 (XQ)	-1L	
$T_{DSPDO\_\{PCIN, CARRYCASCIN, MULTSIGNIN\}\_\{PCOUT, CARRYCASCOUT, MULTSIGNOUT\}}$	{PCIN, CARRYCASCIN, MULTSIGNIN} input to {PCOUT, CARRYCASCOUT, MULTSIGNOUT} output	1.28	1.46	1.72	1.72	2.06	ns
Clock to Outs from Output Register Clock to Output Pins							
$T_{DSPCKO\_\{P, CARRYOUT\}\_PREG}$	CLK (PREG) to {P, CARRYOUT} output	0.38	0.43	0.50	0.50	0.57	ns
$T_{DSPCKO\_\{PCOUT, CARRYCASCOUT, MULTSIGNOUT\}\_PREG}$	CLK (PREG) to {CARRYCASCOUT, PCOUT, MULTSIGNOUT} output	0.50	0.56	0.66	0.66	0.76	ns
Clock to Outs from Pipeline Register Clock to Output Pins							
$T_{DSPCKO\_\{P, CARRYOUT\}\_MREG}$	CLK (MREG) to {P, CARRYOUT} output	1.72	1.96	2.30	2.30	2.69	ns
$T_{DSPCKO\_\{PCOUT, CARRYCASCOUT, MULTSIGNOUT\}\_MREG}$	CLK (MREG) to {PCOUT, CARRYCASCOUT, MULTSIGNOUT} output	1.81	2.06	2.43	2.43	2.88	ns
$T_{DSPCKO\_\{P, CARRYOUT\}\_ADREG\_MULT}$	CLK (ADREG) to {P, CARRYOUT} output	2.79	3.16	3.72	3.72	4.32	ns
$T_{DSPCKO\_\{PCOUT, CARRYCASCOUT, MULTSIGNOUT\}\_ADREG\_MULT}$	CLK (ADREG) to {PCOUT, CARRYCASCOUT, MULTSIGNOUT} output	2.87	3.26	3.84	3.84	4.51	ns
Clock to Outs from Input Register Clock to Output Pins							
$T_{DSPCKO\_\{P, CARRYOUT\}\_\{AREG, BREG\}\_MULT}$	CLK (AREG, BREG) to {P, CARRYOUT} output using multiplier	3.97	4.52	5.36	5.36	6.20	ns
$T_{DSPCKO\_\{P, CARRYOUT\}\_\{AREG, BREG\}}$	CLK (AREG, BREG) to {P, CARRYOUT} output not using multiplier	1.70	1.93	2.27	2.27	2.65	ns
$T_{DSPCKO\_\{P, CARRYOUT\}\_CREG}$	CLK (CREG) to {P, CARRYOUT} output	1.70	1.93	2.27	2.27	2.80	ns
$T_{DSPCKO\_\{P, CARRYOUT\}\_DREG\_MULT}$	CLK (DREG) to {P, CARRYOUT} output	3.89	4.44	5.25	5.25	6.07	ns
Clock to Outs from Input Register Clock to Cascading Output Pins							
$T_{DSPCKO\_\{ACOUT; BCOUT\}\_\{AREG; BREG\}}$	CLK (AREG, BREG) to {P, CARRYOUT} output	0.66	0.76	0.89	0.89	1.01	ns
$T_{DSPCKO\_\{PCOUT, CARRYCASCOUT, MULTSIGNOUT\}\_\{AREG, BREG\}\_MULT}$	CLK (AREG, BREG) to {PCOUT, CARRYCASCOUT, MULTSIGNOUT} output using multiplier	4.05	4.63	5.49	5.49	6.39	ns
$T_{DSPCKO\_\{PCOUT, CARRYCASCOUT, MULTSIGNOUT\}\_\{AREG, BREG\}}$	CLK (AREG, BREG) to {PCOUT, CARRYCASCOUT, MULTSIGNOUT} output not using multiplier	1.79	2.03	2.40	2.40	2.84	ns
$T_{DSPCKO\_\{PCOUT, CARRYCASCOUT, MULTSIGNOUT\}\_DREG\_MULT}$	CLK (DREG) to {PCOUT, CARRYCASCOUT, MULTSIGNOUT} output using multiplier	3.98	4.54	5.38	5.38	6.26	ns
$T_{DSPCKO\_\{PCOUT, CARRYCASCOUT, MULTSIGNOUT\}\_CREG}$	CLK (CREG) to {PCOUT, CARRYCASCOUT, MULTSIGNOUT} output	1.78	2.03	2.40	2.40	2.99	ns

Table 58: **DSP48E1 Switching Characteristics *(Cont'd)***

Symbol	Description	Speed Grade					Units
		-3	-2	-1 (XC)	-1 (XQ)	-1L	
Maximum Frequency							
F_{MAX}	With all registers used	600	540	450	450	410	MHz
F_{MAX_PATDET}	With pattern detector	551	483	408	408	356	MHz
$F_{MAX\_MULT\_NOMREG}$	Two register multiply without MREG	356	311	262	262	224	MHz
$F_{MAX\_MULT\_NOMREG\_PATDET}$	Two register multiply without MREG with pattern detect	327	286	241	241	211	MHz
$F_{MAX\_PREADD\_MULT\_NOADREG}$	Without ADREG	398	347	292	292	254	MHz
$F_{MAX\_PREADD\_MULT\_NOADREG\_PATDET}$	Without ADREG with pattern detect	398	347	292	292	254	MHz
$F_{MAX\_NOPIPELINEREG}$	Without pipeline registers (MREG, ADREG)	266	233	196	196	171	MHz
$F_{MAX\_NOPIPELINEREG\_PATDET}$	Without pipeline registers (MREG, ADREG) with pattern detect	250	219	184	184	160	MHz

Configuration Switching Characteristics

Table 59: **Configuration Switching Characteristics**

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
Power-up Timing Characteristics						
T_{PL}(1)	Program Latency	5	5	5	5	ms, Max
T_{POR}(1)	Power-on-Reset	15/55	15/55	15/55	15/60	ms, Min/Max
T_{ICCK}	CCLK (output) delay	400	400	400	400	ns, Min
$T_{PROGRAM}$	Program Pulse Width	250	250	250	250	ns, Min
Master/Slave Serial Mode Programming Switching						
T_{DCCK}/T_{CCKD}	DIN Setup/Hold, slave mode	4.0/0.0	4.0/0.0	4.0/0.0	4.5/0.0	ns, Min
T_{DSCCK}/T_{SCCKD}	DIN Setup/Hold, master mode	4.0/0.0	4.0/0.0	4.0/0.0	5.0/0.0	ns, Min
T_{CCO}	DOUT at 2.5V	6	6	6	7	ns, Max
	DOUT at 1.8V	6	6	6	7	ns, Max
F_{MCCK}	Maximum CCLK frequency, serial modes	105	105	105	70	MHz, Max
$F_{MCCKTOL}$	Frequency Tolerance, master mode with respect to nominal CCLK.	55	55	55	60	%
F_{MSCCK}	Slave mode external CCLK	100	100	100	100	MHz
SelectMAP Mode Programming Switching						
T_{SMDCCK}/T_{SMCCKD}	SelectMAP Data Setup/Hold	4.0/0.0	4.0/0.0	4.0/0.0	5.5/0.0	ns, Min
$T_{SMCSCCK}/T_{SMCCKCS}$	CSI_B Setup/Hold	4.0/0.0	4.0/0.0	4.0/0.0	5.5/0.0	ns, Min
T_{SMCCKW}/T_{SMWCCK}	RDWR_B Setup/Hold	10.0/0.0	10.0/0.0	10.0/0.0	16.0/0.0	ns, Min
$T_{SMCKCSO}$	CSO_B clock to out (330 Ω pull-up resistor required)	6	6	6	7	ns, Max
T_{SMCO}	CCLK to DATA out in readback at 2.5V	6	6	6	7	ns, Max
	CCLK to DATA out in readback at 1.8V	6	6	6	7	ns, Max

Table 59: **Configuration Switching Characteristics *(Cont'd)***

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
T_{SMCKBY}	CCLK to BUSY out in readback at 2.5V	6	6	6	7	ns, Max
	CCLK to BUSY out in readback at 1.8V	6	6	6	7	ns, Max
F_{SMCCK}	Maximum Frequency with respect to nominal CCLK	100	100	100	70	MHz, Max
F_{RBCCK}	Maximum Readback Frequency with respect to nominal CCLK	100	100	100	60	MHz, Max
$F_{MCCKTOL}$	Frequency tolerance, master mode with respect to nominal CCLK	55	55	55	60	%
Boundary-Scan Port Timing Specifications						
T_{TAPTCK}/T_{TCKTAP}	TMS and TDI Setup time before TCK/ Hold time after TCK	3.0/2.0	3.0/2.0	3.0/2.0	4.0/2.0	ns, Min
T_{TCKTDO}	TCK falling edge to TDO output valid at 2.5V	6	6	6	7	ns, Max
	TCK falling edge to TDO output valid at 1.8V	6	6	6	7	ns, Max
F_{TCK}	Maximum configuration TCK clock frequency	66	66	66	33	MHz, Max
F_{TCKB_MIN}	Minimum boundary-scan TCK clock frequency when using IEEE Std 1149.6 (AC-JTAG). Minimum operating temperature for IEEE Std 1149.6 is 0°C.	15	15	15	15	MHz, Min
F_{TCKB}	Maximum boundary-scan TCK clock frequency	66	66	66	33	MHz, Max
BPI Master Flash Mode Programming Switching						
T_{BPICCO}[(2)]	ADDR[25:0], RS[1:0], FCS_B, FOE_B, FWE_B outputs valid after CCLK rising edge at 2.5V	6	6	6	7	ns
	ADDR[25:0], RS[1:0], FCS_B, FOE_B, FWE_B outputs valid after CCLK rising edge at 1.8V	6	6	6	7	ns
T_{BPIDCC}/T_{BPICCD}	Setup/Hold on D[15:0] data input pins	4.0/0.0	4.0/0.0	4.0/0.0	5.0/0.0	ns
$T_{INITADDR}$	Minimum period of initial ADDR[25:0] address cycles	3	3	3	3	CCLK cycles
SPI Master Flash Mode Programming Switching						
$T_{SPIDCC}/T_{SPIDCCD}$	DIN Setup/Hold before/after the rising CCLK edge	3.0/0.0	3.0/0.0	3.0/0.0	3.5/0.0	ns
T_{SPICCM}	MOSI clock to out at 2.5V	6	6	6	7	ns
	MOSI clock to out at 1.8V	6	6	6	7	ns
$T_{SPICCFC}$	FCS_B clock to out at 2.5V	6	6	6	7	ns
	FCS_B clock to out at 1.8V	6	6	6	7	ns
$T_{FSINIT}/T_{FSINITH}$	FS[2:0] to INIT_B rising edge Setup and Hold	2	2	2	2	µs
CCLK Output (Master Modes)						
T_{MCCKL}	Master CCLK clock Low time duty cycle	45/55	45/55	45/55	40/60	%, Min/Max
T_{MCCKH}	Master CCLK clock High time duty cycle	45/55	45/55	45/55	40/60	%, Min/Max
CCLK Input (Slave Modes)						
T_{SCCKL}	Slave CCLK clock minimum Low time	2.5	2.5	2.5	2.5	ns, Min
T_{SCCKH}	Slave CCLK clock minimum High time	2.5	2.5	2.5	2.5	ns, Min
Dynamic Reconfiguration Port (DRP) for MMCM Before and After DCLK						
F_{DCK}	Maximum frequency for DCLK	200	200	200	200	MHz
$T_{MMCMDCK\_DADDR}$/ $T_{MMCMCKD\_DADDR}$	DADDR Setup/Hold	1.25/ 0.00	1.40/ 0.00	1.63/ 0.00	1.64/ 0.00	ns

Table 67: **Clock-Capable Clock Input to Output Delay With MMCM**

Symbol	Description	Device	Speed Grade				Units
			-3	-2	-1	-1L	
LVCMOS25 Clock-capable Clock Input to Output Delay using Output Flip-Flop, 12mA, Fast Slew Rate, *with* MMCM.							
$T_{ICKOFMMCMCC}$	Clock-capable Clock Input and OUTFF *with* MMCM	XC6VLX75T	2.22	2.38	2.63	2.72	ns
		XC6VLX130T	2.24	2.39	2.65	2.74	ns
		XC6VLX195T	2.24	2.40	2.65	2.75	ns
		XC6VLX240T	2.24	2.40	2.65	2.75	ns
		XC6VLX365T	2.25	2.42	2.65	2.76	ns
		XC6VLX550T	N/A	2.43	2.68	2.80	ns
		XC6VLX760	N/A	2.42	2.69	2.79	ns
		XC6VSX315T	2.23	2.38	2.65	2.73	ns
		XC6VSX475T	N/A	2.30	2.57	2.66	ns
		XC6VHX250T	2.25	2.41	2.67	N/A	ns
		XC6VHX255T	2.35	2.51	2.78	N/A	ns
		XC6VHX380T	2.27	2.43	2.69	N/A	ns
		XC6VHX565T	N/A	2.41	2.68	N/A	ns
		XQ6VLX130T	N/A	2.39	2.65	2.74	ns
		XQ6VLX240T	N/A	2.40	2.65	2.75	ns
		XQ6VLX550T	N/A	N/A	2.68	2.80	ns
		XQ6VSX315T	N/A	2.38	2.65	2.73	ns
		XQ6VSX475T	N/A	N/A	2.57	2.66	ns

Notes:

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. MMCM output jitter is already included in the timing calculation.

Table 72: **Package Skew**

Symbol	Description	Device	Package	Value	Units
$T_{PKGSKEW}$	Package Skew(1)	XC6VLX75T	FF484	95	ps
			FF784	146	ps
		XC6VLX130T	FF484	95	ps
			FF784	146	ps
			FF1156	165	ps
		XC6VLX195T	FF784	145	ps
			FF1156	182	ps
		XC6VLX240T	FF784	146	ps
			FF1156	182	ps
			FF1759	187	ps
		XC6VLX365T	FF1156	189	ps
			FF1759	184	ps
		XC6VLX550T	FF1759	196	ps
			FF1760	249	ps
		XC6VLX760	FF1760	236	ps
		XC6VSX315T	FF1156	168	ps
			FF1759	190	ps
		XC6VSX475T	FF1156	168	ps
			FF1759	204	ps
		XC6VHX250T	FF1154	166	ps
		XC6VHX255T	FF1155	168	ps
			FF1923	228	ps
		XC6VHX380T	FF1154	159	ps
			FF1155	172	ps
			FF1923	227	ps
			FF1924	220	ps
		XC6VHX565T	FF1923	232	ps
			FF1924	197	ps
		XQ6VLX130T	RF784	146	ps
			RF1156	165	ps
			FFG1156	165	ps
		XQ6VLX240T	RF784	146	ps
			RF1156	182	ps
			FFG1156	182	ps
			RF1759	187	ps
		XQ6VLX550T	RF1759	196	ps
		XQ6VSX315T	RF1156	168	ps
			FFG1156	168	ps
			RF1759	190	ps
		XQ6VSX475T	RF1156	168	ps
			FFG1156	168	ps
			RF1759	204	ps

Notes:

1. These values represent the worst-case skew between any two SelectIO resources in the package: shortest flight time to longest flight time from Pad to Ball (7.0 ps per mm).
2. Package trace length information is available for these device/package combinations. This information can be used to deskew the package.

Date	Version	Description of Revisions
01/18/10	2.1	Changed absolute maximum ratings for both V_{IN} and V_{TS} in Table 1. Added data to Table 3. Added data to Table 5. Updated SSTL15 in Table 7. Updated V_{OCM} and V_{OD} values in Table 8. Added eFUSE endurance Table 12. Added values to $V_{MGTREFCLK}$ and V_{IN} in Table 13, page 11. Added values and updated tables in the GTX Transceiver Specifications and GTH Transceiver Specifications sections. Added Table 27 and Figure 4. Revised parameters and values in Table 39. Updated Table 40, page 23. Added data to Table 41. Updated speed specification to v1.04 with appropriate changes to Table 42 and Table 43 including production release of the XC6VLX240T for -1 and -2 speed grades. Speed specification changes and numerous updates also made to Table 44, and Table 49 through Table 71. Added data to Table 73 and Table 74.
02/09/10	2.2	Revised description of C_{IN} in Table 3. Clarified values in Table 5. Fixed SDR LVDS unit error in Table 41.
04/12/10	2.3	Added note 3 and update value of *n* in Table 3. Clarified simultaneous power-down in Power-On Power Supply Requirements. Updated external reference junction temperatures in Table 40, Analog-to-Digital Specifications. Updated speed specification to v1.05 with appropriate changes to Table 42 and Table 43 including production release of the XC6VLX130T for -1 and -2 speed grades. Fixed note 4 in Table 48. Increased the -2 specification for $F_{IDELAYCTRL\_REF}$ and clarified units for $T_{IDELAYPAT\_JIT}$ in Table 53. Added note 1 to Table 62.
05/11/10	2.4	Updated F_{RXREC} in Table 22. Revised $F_{IDELAYCTRL\_REF}$ in Table 53. Removed $T_{RCKO\_PARITY\_ECC}$: Clock CLK to ECCPARITY in standard ECC mode row in Table 57. Added XC6VLX130T values to Table 72.
05/26/10	2.5	Added XC6VLX195T data to Table 5. Updated values in Table 22 including adding note 2 and note 3. Updated speed specification to v1.06 with appropriate changes to Table 42 and Table 43 including production release of the XC6VLX195T for -1 and -2 speed grades. Added XC6VLX195T values to Table 72.
07/16/10	2.6	Changed Table 42 and Table 43 to production status on the -3 speed grade XC6VLX130T, XC6VLX195T, and XC6VLX240T devices. Added XC6VHX250Tdata to Table 4 and Table 72. Added Note 6 to Table 64.
07/23/10	2.7	Changed Table 42 and Table 43 to production status on the XC6VLX75T, XC6VLX365T, XC6VLX550T, XC6VLX760, XC6VSX315T, and XC6VSX475T devices using ISE 12.2 software with speed specification v1.08. Updated $V_{CMOUTDC}$ equation to MGTAVTT – D_{VPPOUT}/4 in Table 17. Updated some -3, -2, -1 specifications in Table 65 through Table 72. Added and updated -1L specifications to Table 41 and for most switching characteristics tables.
07/30/10	2.8	Changed Table 42 and Table 43 to production status on the -1L speed grade for the XC6VLX130T, XC6VLX195T, XC6VLX240T, XC6VLX365T, and XC6VLX550T devices using ISE 12.2 software with current speed specifications. Also updated the speed specifications for XC6VLX75T, XC6VLX550T, and XC6VSX315T. Updated V_{CCINT} specifications for -1L speed grade industrial temperature range devices in Table 2.
09/20/10	2.9	In Table 32, changed $F_{GPLLMAX}$ specification in -3 column from 5.951 to 5.591. In Table 40, changed F_{MAX} for the DCLK from 250 MHz to 80 MHz.
10/18/10	2.10	The specification change in version 2.9, Table 40 is described in XCN10032, *Virtex-6 FPGA: GTX Transceiver User Guide, Family Data Sheet (SYSMON DCLK), and JTAG ID Changes* In this version (2.10), -1L(I) data is added to Table 4 and clarified in Note 2. Changed Table 42 and Table 43 to production status on the -1L speed grade XC6VLX75T, XC6VLX760, XC6VSX315T, and XC6VSX475T devices using ISE 12.3 software with current speed specifications. Revised the XC6VLX760 -1L speed specification for $T_{PHMMCMGC}$ in Table 69 and $T_{PHMMCMCC}$ in Table 70.
01/17/11	2.11	Changed in Table 42 and Table 43 to production status on the XC6VHX250T devices using ISE 12.4 software with current speed specifications. Added industrial temperature range (T_j) recommended specifications to Table 2; including specific ranges for the -2I XC6VSX475T, XC6VLX550T, XC6VLX760, and XC6VHX565Tdevices. Added note 3 to Table 36 and maximum total jitter values. Added note 4 to Table 37 and maximum sinusoidal jitter values. Added note 2 to Table 43. Revised F_{MAX} descriptions in Table 57 and added note 12. Added note 8 to F_{PFDMIN} in Table 64. The following revisions are due to specification changes as described in XCN11009, *Virtex-6 FPGA: Data Sheet, User Guides, and JTAG ID Updates*. In Table 59:*Configuration Switching Characteristics*, page 49, revised -1L specifications for T_{POR}, F_{MCCK}, $F_{MCCKTOL}$, $T_{SMCSCCK}$, T_{SMCCKW}, F_{RBCCK}, F_{TCK}, F_{TCKB}, T_{MCCKL}, and T_{MCCKH}. In Table 64: *MMCM Specification*, added bandwidth settings to F_{PFDMIN} and added note 1.